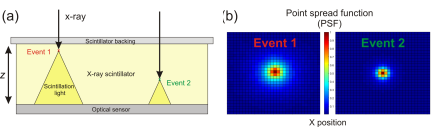




Single x-ray imaging (SXI) of depth-localized interactions in scintillators

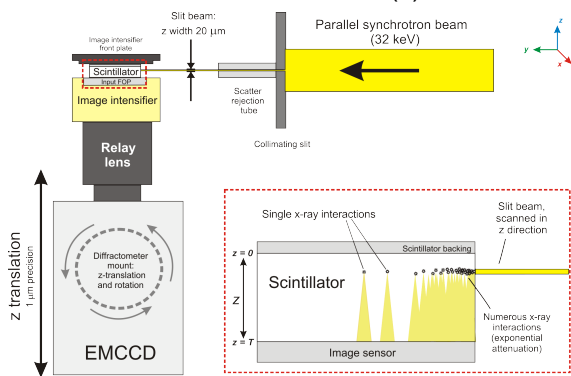
Background: Depth-dependence in scintillator gain, spatial blur degrades DQE(f) of indirect flat panel detectors



Motivation: Explore FPD designs to maximize scintillator thickness for dose-efficiency, and minimize loss in DQE(f) due to depth effects

Approach: Image depth-localized single x-ray interactions in scintillators¹

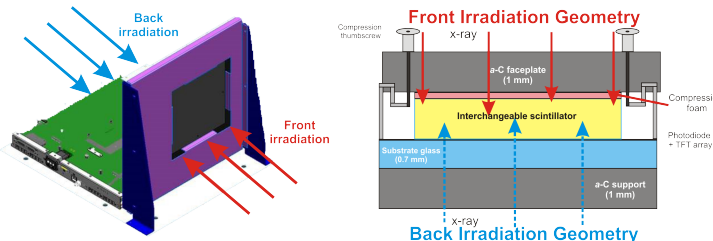
Parallel synchrotron beam ($\Delta z = 20 \mu\text{m}$, 32 keV) scanned in scintillator thickness (z) dimension



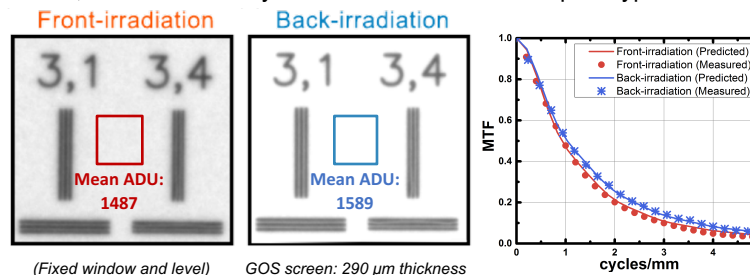
Improving detector performance with "back-irradiation"

We have constructed a prototype flat panel detector allowing both "front-irradiation" (FI) and "back-irradiation" (BI) of an interchangeable scintillator

BI (first proposed by Fuji)² can be leveraged to push scintillator design limits



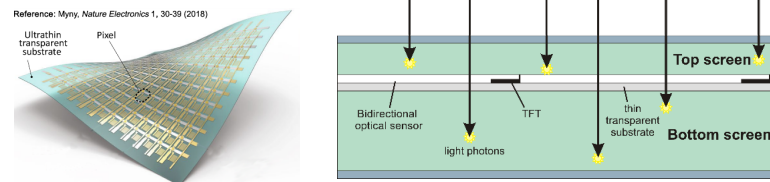
Spatial resolution and x-ray sensitivity of FI and BI are predicted using results from SXI, and confirmed by direct measurements with prototype FPD



Dual-screen indirect flat panel detector

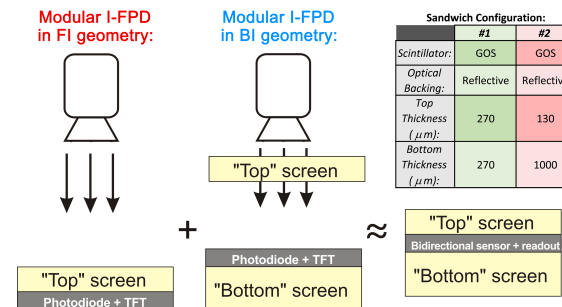
Recent advances in ultra-thin (<30 μm), flexible TFT technology are enabling novel, multilayer FPD structures, for example:

Dual-screen "sandwich" detector comprising a FI "top" screen and BI "bottom" screen in contact with a bidirectional-sensing photodiode/TFT array³



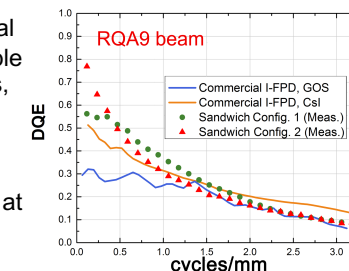
Dual-screen I-FPD performance estimation

Predict dual-screen I-FPD by linear combination of FI "top" screen image and filtered BI "bottom" screen image



Superior DQE at low spatial frequencies and comparable DQE at higher frequencies, compared to current detectors

Particularly advantageous at higher x-ray energies (e.g. RQA9, cone-beam CT)



Conclusions

Direct knowledge of $g(z)$ and $\text{MTF}(z, f)$ informs potential I-FPD improvements through BI and dual-screen design concepts, which can be explored using a modular, bi-directional FPD.

References

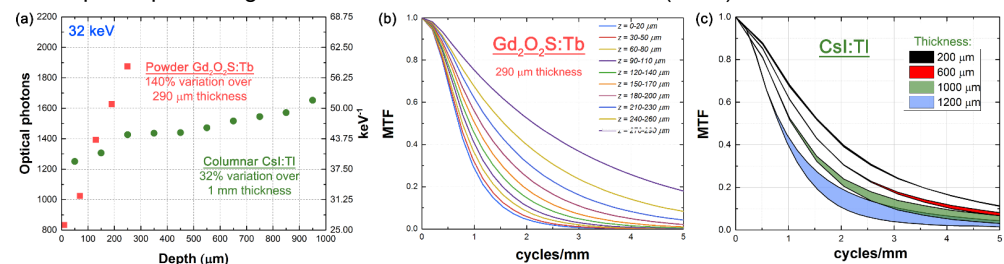
- [1] A. Howansky, et al., Proc. SPIE, 10132, (2017).
- [2] A. Takasu, et al., Proc. SPIE, 6510, (2007).
- [3] A. R. Lubinsky, et al., Proc. SPIE 10573, (2018).

Acknowledgements

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Direct measurements of depth-dependent scintillator gain and blur

Depth-dependent gain and MTF measured in $\text{Gd}_2\text{O}_2\text{S:Tb}$ (GOS) and CsI:Tl scintillators



Validation of depth-localized gain and blur measurements

SXI measurements used to calculate scintillator presampling $\text{MTF}(f)$ in energy-integrating detector

Excellent agreement with slanted-edge measurements made using CMOS image sensor (48 μm pixel)

